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B/O Form PTO-1449	Atty. Docket Number BEVA3004D/REF	Serial Number Divisional of 09/486,715
U.S. Department of Commerce Patent and Trademark Office	Applicant BEVAN et al.	
Information Disclosure Statement by Applicant	Filing Date	Group
	August 5, 2003	1743

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EXAMINER: Initial if citation is considered, whether or no t citation is in conf ormance with MPEP 609; Draw a line thr ough citation if no t in conformance and not considered. Include copy of this form with next communication to applicant.

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